

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	21	(US-20050122352-\$ or US-20040263544-\$ or US-20030063174-\$ or US-20050140751-\$ or US-20020105566-\$ or US-20020003551-\$).did. or (US-5572241-\$ or US-5369420-\$ or US-6467862-\$ or US-6012793-\$ or US-5400066-\$ or US-6679582-\$ or US-6431678-\$ or US-6402277-\$ or US-5953031-\$ or US-5428378-\$ or US-6074036-\$ or US-6929356-\$). did. or (JP-06143612-\$ or JP-05270007-\$ or JP-04320853-\$). did.	US-PGPUB; USPAT; JPO	OR	ON	2005/09/29 08:24
L2	6	1 and polyimide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:39
L5	13	1 and voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:49
L9	685686	(sequentially "in turn")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:55
L10	102730	(sequentially "in turn") and electrode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:55
L11	20354	(sequentially "in turn") and electrode and leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:55
L12	635	(sequentially "in turn") and electrode and leak\$4 and "347"/\$. ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:55

L13	85	(sequentially "in turn") with electrode and leak\$4 and "347"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 09:56
S1	417	"347"/\$.ccls. and leak\$4 and electrode with (channel conduit passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/26 16:40
S2	13	"347"/19.ccls. and leak\$4 and electrode with (channel conduit passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/26 16:40
S3	417	"347"/\$.ccls. and leak\$4 and electrode with (channel conduit passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 08:53
S4	13	"347"/19.ccls. and leak\$4 and electrode with (channel conduit passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 08:35
S5	12	"347"/7.ccls. and leak\$4 and electrode with (channel conduit passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 09:21
S7	29	"347"/6.ccls. and leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 09:26
S11	246	"347"/\$.ccls. and (detect\$3 identify find\$4 discover\$3) with leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 09:31

S12	139	"347"/\$.ccls. and (detect\$3 identify find\$4 discover\$3) with leak\$4 and electrode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 10:44
S15	664	"347"/\$.ccls. and capillary with tube	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 10:27
S16	220	"347"/\$.ccls. and (capillary with tube) and leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 10:28
S18	70	"347"/\$.ccls. and (capillary ink) with tube and (detect\$3 identify find\$4 discover\$3) with leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 10:30
S22	8316	ink near5 leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:30
S23	58640	detect\$4 with leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:30
S24	2133219	voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:31
S25	1637013	electrode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:31

S27	191755	electrode with (passage chamber channel conduit)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:31
S28	270529	cartridge	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:32
S29	39350	cross near3 talk	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:32
S30	65	S22 and S23 and S24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 13:40
S31	14937	(S22 S23).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:34
S32	1892	S31 and S24	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:35
S33	79	S31 and S24 and S27	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 11:35
S35	288893	leak\$4.ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 13:43

S36	715	"347"/\$.ccls. and S35	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:07
S37	50	S36 and S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 13:43
S38	281	"347"/6.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:08
S39	299	"347"/96.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:08
S40	21	"347"/96.ccls. and (leak\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:15
S42	80	137/15.11.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:33
S43	257	347/19.ccls. and (conductor metal electrode) same (passage channel conduit chamber)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:48
S45	5	347/19.ccls. and (conductor metal electrode) same (passage channel conduit chamber) and (detect\$3 identif\$3 find\$3) near\$5 leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 15:57
S46	4	("5572241").URPN.	USPAT	OR	ON	2005/09/27 15:52

S47	9	347/19.ccls. and (conductor metal electrode sensor) same (passage channel conduit chamber) and (detect\$3 identif\$3 find\$3) near5 leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:01
S48	2	347/23.ccls. and (conductor metal electrode sensor) same (passage channel conduit chamber) and (detect\$3 identif\$3 find\$3) near5 leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:01
S50	452358	(su chang chen lee chou).in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:38
S51	998	(su chang chen lee chou).in. and leak\$4.ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:39
S52	33	(su chang chen lee chou).in. and leak\$4.ti. and electrode.clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:42
S53	17	(su chang chen lee chou).in. and leak\$4.ti. and (electrode and leak\$4).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:44
S54	856	"347"/\$.ccls. and cross near3 talk	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/27 16:55

S55	19	(US-20050122352-\$ or US-20040263544-\$ or US-20030063174-\$ or US-20050140751-\$ or US-20020105566-\$ or US-20020003551-\$).did. or (US-5572241-\$ or US-5369420-\$ or US-6467862-\$ or US-6012793-\$ or US-5400066-\$ or US-6679582-\$ or US-6431678-\$ or US-6402277-\$ or US-5953031-\$ or US-5428378-\$). did. or (JP-06143612-\$ or JP-05270007-\$ or JP-04320853-\$). did.	US-PGPUB; USPAT; JPO	OR	ON	2005/09/28 10:03
S60	10	(individual\$3 independent\$3) and S55	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 09:26
S63	3	(individual\$3 independent\$3) same voltage and S55	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 09:28
S64	3	(individual\$3 independent\$3) same electrode and S55	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 09:29
S71	4	S55 and display	US-PGPUB; USPAT; JPO	OR	ON	2005/09/28 10:45
S73	3	"6679582"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 10:52
S74	16	control\$3 and S55	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 11:15
S75	615	"347"/\$.ccls. and printhead same glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 11:15

S76	42	"347"/20.ccls. and printhead same glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 11:20
S77	6	S55 and glass	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 11:49
S79	0	nozzle with polyimide and 347/20.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 11:50
S80	3	nozzle with polyimide and "347"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 12:18
S81	714	347/87.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 12:18
S82	373	347/87.ccls. and leak\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 12:18
S83	306	347/87.ccls. and leak\$4 and (electrode conductor pad contact)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 12:19
S84	130	347/87.ccls. and leak\$4 and (electrode conductor pad contact) with (channel path conduit chamber)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 12:20

S85	16	347/87.ccls. and leak\$4.ab. and (electrode conductor pad contact) with (channel path conduit chamber)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 12:25
S86	24	347/86.ccls. and leak\$4.ab. and (electrode conductor pad contact) with (channel path conduit chamber)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 14:06
S87	34	347/86.ccls. and leak\$4 adj between	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 14:57
S88	3	347/86.ccls. and leak\$4 adj between near (channel conduit chamber passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 14:59
S89	0	347/87.ccls. and leak\$4 adj between near (channel conduit chamber passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 14:59
S90	11	"347"/\$.ccls. and leak\$4 adj between near (channel conduit chamber passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 15:10
S91	5	S90 and (conductor electrode pad contact) with (channel passage conduit chamber)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 15:08
S92	3	"101"/\$.ccls. and leak\$4 adj between near (channel conduit chamber passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 15:24

S93	172	"347"/\$.ccls. and leak\$4 near5 between near5 (channel conduit chamber passage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 15:29
S95	47	"347"/\$.ccls. and leak\$4 near5 between near5 (channel conduit chamber passage) and detect\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/28 15:30